- Meets or Exceeds the Requirements of ANSI EIA/TIA-422-B and ITU Recommendation V.11
- Single 5-V Supply
- Balanced Line Operation
- TTL Compatible
- High-Impedance Output State for Party-Line Applications
- High-Current Active-Pullup Outputs
- Short-Circuit Protection
- Dual Channels
- Clamp Diodes at Inputs

#### (TOP VIEW) ∏∨<sub>CC</sub> 1Z[ 2 13 **∏** 2Z 1Y[] 3 ∏ 2Y 12 1AΠ П 2В 4 11 1В[ 5 7 2A 10 12EN 1EN[ 6 9 GND ∏ Пис 8

D OR N PACKAGE

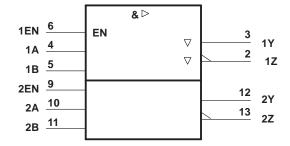
NC-No internal connection

### description

The SN75159 dual differential line driver with 3-state outputs is designed to provide all the features of the SN75158 line driver with the added feature of driver output controls. There is an individual control for each driver. When the output control is low, the associated outputs are in a high-impedance state and the outputs can neither drive nor load the bus. This permits many devices to be connected together on the same transmission line for party-line applications.

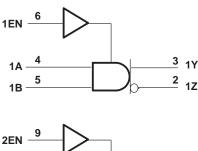
The SN75159 is characterized for operation from 0°C to 70°C.

# logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

# logic diagram (positive logic)



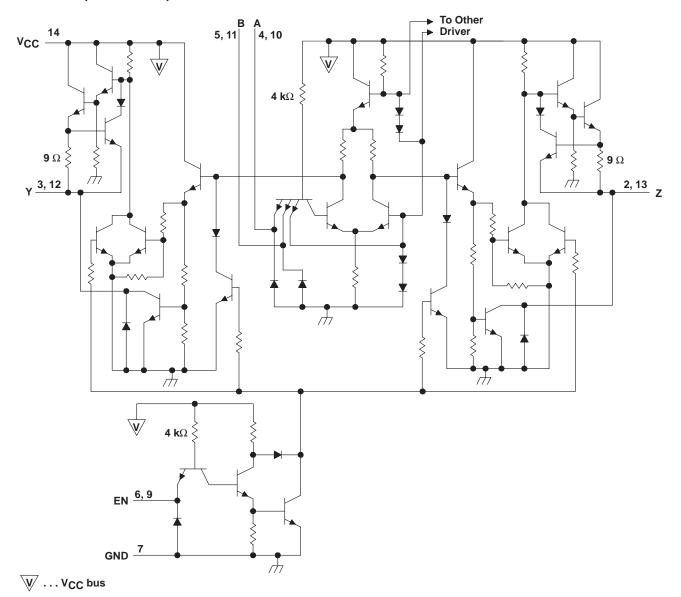




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# schematic (each driver)



Resistor values shown are nominal.



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub> (see Note 1)	7 \
Input voltage, V <sub>I</sub>	
Off-state voltage applied to open-collector outputs	
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range, T <sub>stq</sub>	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW
N	1150 mW	9.2 mW/°C	736 mW

# recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	4.75	5	5.25	V
High-level input voltage, VIH	2			V
Low-level input voltage, V <sub>IL</sub>			0.8	V
High-level output voltage, I <sub>OH</sub>			-40	mA
Low-level output current, I <sub>OL</sub>			40	mA
Operating free-air temperature, T <sub>A</sub>	0		70	°C



<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values except differential output voltage VOD are with respect to the network ground terminal. VOD is at the Y output with respect to the Z output.

# SN75159 **DUAL DIFFERENTIAL LINE DRIVER** WITH 3-STATE OUTPUTS

SLLS088B - JANUARY 1977 - REVISED MAY 1995

# electrical characteristics over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP <sup>†</sup>	MAX	UNIT	
VIK	Input clamp voltage	V <sub>CC</sub> = 4.75 V,	$I_{I} = -12 \text{ mA}$			-0.9	-1.5	V	
VOH	High-level output voltage	V <sub>CC</sub> = 4.75 V, V <sub>IH</sub> = 2 V,	$V_{IL} = 0.8 \text{ V},$ $I_{OH} = -40 \text{ mA}$	1	2.4	3		٧	
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = 4.75 V, V <sub>IH</sub> = 2 V,	$V_{IL} = 0.8 \text{ V},$ $I_{OL} = 40 \text{ mA}$			0.25	0.4	٧	
Vок	Output clamp voltage	V <sub>CC</sub> = 5.25 V,	$I_O = -40 \text{ mA}$			-1.1	-1.5	V	
۷o	Output voltage	$V_{CC} = 4.75 \text{ V to } 5.25 \text{ V},$	IO = 0		0		6	V	
V <sub>OD1</sub>	Differential output voltage	$V_{CC} = 5.25 \text{ V},$	I <sub>O</sub> = 0			3.5	2V <sub>OD2</sub>	V	
VOD2	Differential output voltage	V <sub>CC</sub> = 4.75 V	_		2	3		V	
ΔIVODI	Change in magnitude of differential output voltage‡	V <sub>CC</sub> = 4.75 V				±0.02	±0.4	٧	
V00	Common-mode output	V <sub>CC</sub> = 5.25 V	] <sub>B. = 100 0</sub>	Soo Eiguro 1		1.8	3	V	
Voc	voltage§	V <sub>CC</sub> = 4.75 V	$R_L$ = 100 Ω, See Figure 1			1.5	3	V	
∆IVocI	Change in magnitude of common-mode output voltage‡	V <sub>CC</sub> = 4.75 V to 5.25 V				±0.01	±0.4	٧	
			V <sub>O</sub> = 6 V			0.1	100		
IO	Output current with power off	$V_{CC} = 0$	$V_O = -0.25 \text{ V}$ $V_O = -0.25 \text{ V to 6 V}$			-0.1	-100	μΑ	
							±100		
			T <sub>A</sub> = 25°C	$V_O = 0$ to $V_{CC}$			±10		
	Off-state (high-impedance state) output current	V <sub>CC</sub> = 5.25 V, Output controls at 0.8 V	T <sub>A</sub> = 70°C	VO = 0			-20		
loz				V <sub>O</sub> = 0.4 V			±20	μΑ	
				V <sub>O</sub> = 2.4 V			±20		
				AO = ACC			20		
łı	Input current at maximum input voltage	V <sub>CC</sub> = 5.25 V,	V <sub>I</sub> = 5.5 V				1	mA	
lН	High-level input current	V <sub>CC</sub> = 5.25 V,	V <sub>I</sub> = 2.4 V				40	μΑ	
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = 5.25 V,	V <sub>I</sub> = 0.4 V			-1	-1.6	mA	
los	Short-circuit output current¶	V <sub>CC</sub> = 5.25 V			-40	-90	-150	mA	
Icc	Supply current (both drivers)	V <sub>CC</sub> = 5.25 V, T <sub>A</sub> = 25°C,	Inputs grounded, No load			47	65	mA	

 $<sup>\</sup>dagger$  All typical values are at V<sub>CC</sub> = 5 V and T<sub>A</sub> = 25°C except for V<sub>OC</sub>, for which V<sub>CC</sub> is as stated under test conditions.



 $<sup>\</sup>pm \Delta |V_{OD}|$  and  $\Delta |V_{OC}|$  are the changes in magnitudes of  $V_{OD}$  and  $V_{OC}$ , respectively, that occur when the input is changed from a high level to a low

<sup>§</sup> In ANSI Standard EIA/TIA-422-B, V<sub>OC</sub>, which is the average of the two output voltages with respect to GND, is called output offset voltage, V<sub>OS</sub>. ¶ Only one output should be shorted at a time, and duration of the short circuit should not exceed one second.

# switching characteristics over operating free-air temperature range, $V_{CC} = 5 \text{ V}$

	PARAMETER	TEST CONDITIONS		TYP <sup>†</sup>	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low-to-high-level output	$C_L = 30$ pF, $R_L = 100 \Omega$ , See Figure 2	,	16	25	ns
<sup>t</sup> PHL	Propagation delay time, high-to-low-level output	Termination A		11	20	ns
<sup>t</sup> PLH	Propagation delay time, low-to-high-level output	C <sub>L</sub> = 15 pF, See Figure 2, Termination	,	13	20	ns
tPHL	Propagation delay time, high-to-low-level output	CL = 15 pr, See rigule 2, Termination	7	9	15	ns
tTLH	Transition time, low-to-high-level output	$C_L = 30 \text{ pF}, R_L = 100 \Omega, See Figure 2$	,	4	20	ns
tTHL	Transition time, high-to-low-level output	Termination A		4	20	ns
<sup>t</sup> PZH	Output enable time to high level	$C_L = 30 \text{ pF},  R_L = 180 \Omega,  \text{See Figure 3}$		7	20	ns
tPZL	Output enable time to low level	$C_L = 30 \text{ pF},  R_L = 250 \Omega,  \text{See Figure 4}$		14	40	ns
<sup>t</sup> PHZ	Output disable time from high level	$C_L = 30 \text{ pF}, R_L = 180 \Omega, See Figure 3$		10	30	ns
t <sub>PLZ</sub>	Output disable time from low level	$C_L = 30 \text{ pF},  R_L = 250 \Omega,  \text{See Figure 4}$		17	35	ns
	Overshoot factor	$R_L = 100 \Omega$ , See Figure 2, Termination	С		10%	

<sup>†</sup> All typical values are at T<sub>A</sub> = 25°C.

#### **SYMBOL EQUIVALENTS**

DATA-SHEET PARAMETER	EIA/TIA-422-B
VO	V <sub>oa</sub> , V <sub>ob</sub>
V <sub>OD1</sub>	V <sub>O</sub>
V <sub>OD2</sub>	V <sub>t</sub>
Δ V <sub>OD</sub>	$  V_t  -  \overline{V}_t  $
Voc	V <sub>os</sub>
Δ VOC	$ V_{OS} - \overline{V}_{OS} $
los	I <sub>sa</sub>   ,  I <sub>sb</sub>
Ю	I <sub>xa</sub>   ,  I <sub>xb</sub>

## PARAMETER MEASUREMENT INFORMATION

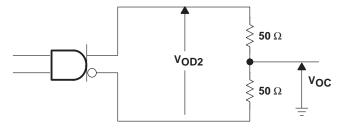
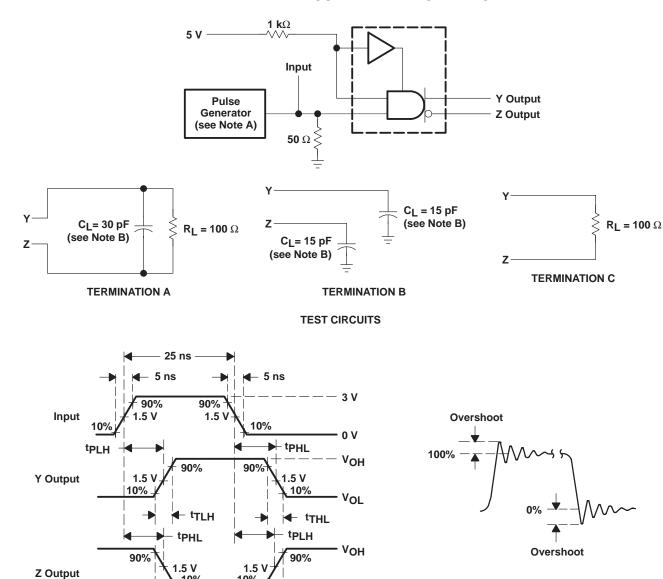


Figure 1. Differential and Common-Mode Output Voltages

### PARAMETER MEASUREMENT INFORMATION



**VOLTAGE WAVEFORMS** 

 $v_{OL}$ 

NOTES: A. The pulse generator has the following characteristics:  $Z_O = 50 \Omega$ , PRR  $\leq 10 \text{ MHz}$ .

10%

B. C<sub>L</sub> includes probe and jig capacitance.

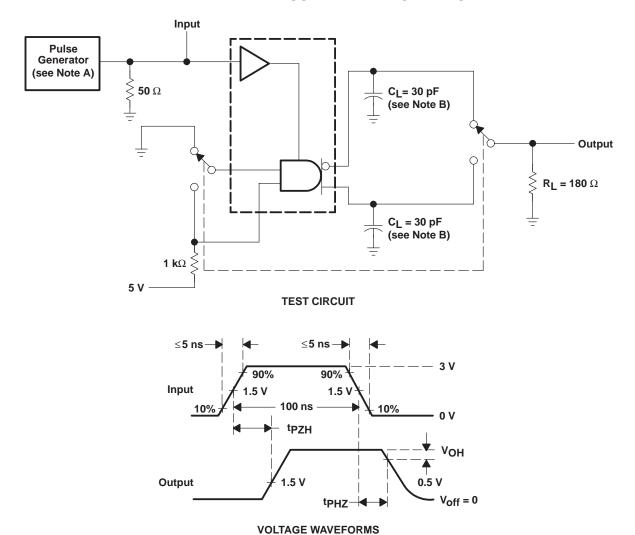
10%

- tTHL

Figure 2. Test Circuits, Voltage Waveforms, and Overshoot Factor



## PARAMETER MEASUREMENT INFORMATION

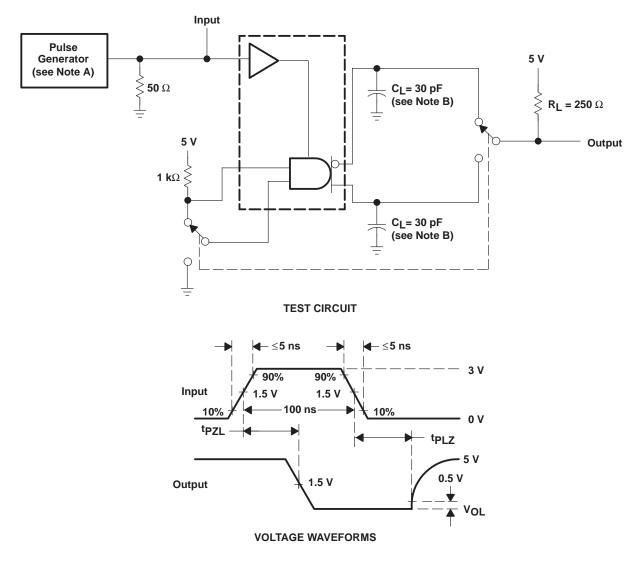


NOTES: A. The pulse generator has the following characteristics: Z<sub>O</sub> = 50  $\Omega$ , PRR  $\leq$  500 kHz.

B. C<sub>L</sub> includes probe and jig capacitance.

Figure 3. Test Circuit and Voltage Waveforms

### PARAMETER MEASUREMENT INFORMATION



NOTES: A. The pulse generator has the following characteristics: Z<sub>O</sub> = 50  $\Omega$ , PRR  $\leq$  500 kHz.

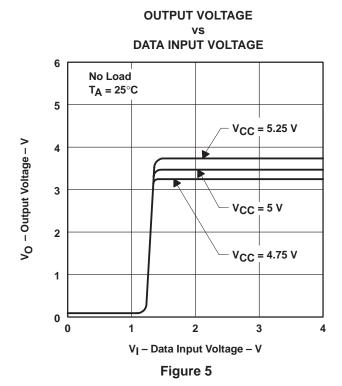
B. C<sub>L</sub> includes probe and jig capacitance.

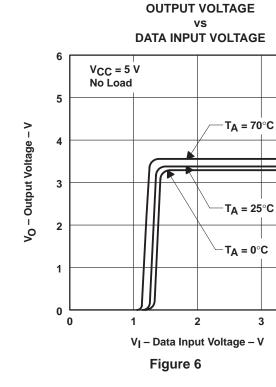
Figure 4. Test Circuit and Voltage Waveform

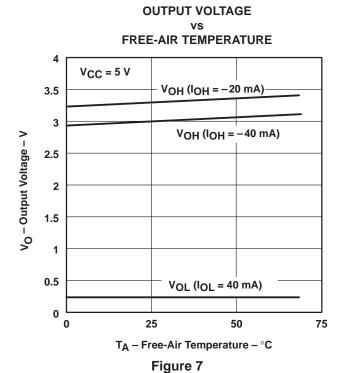


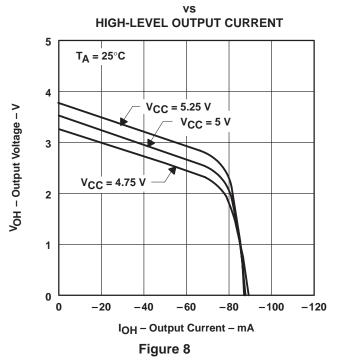
3

### **TYPICAL CHARACTERISTICS**



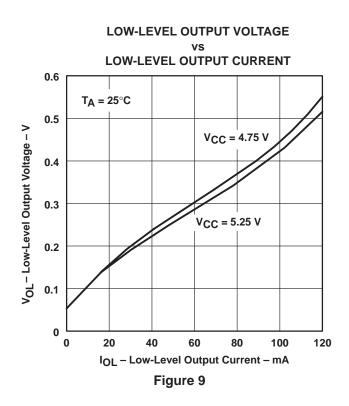


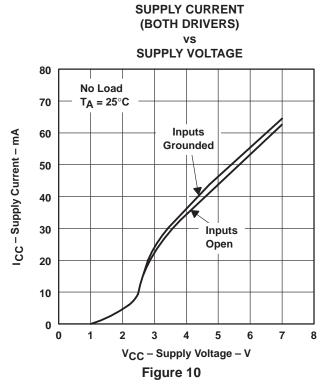


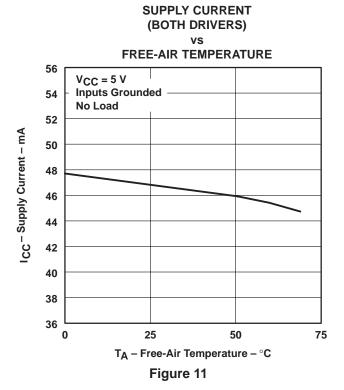


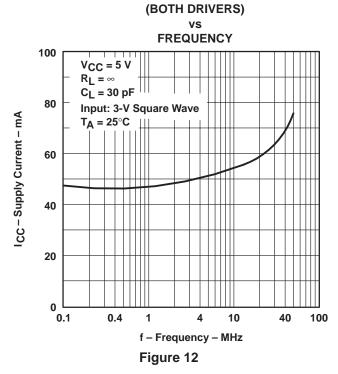
**HIGH-LEVEL OUTPUT VOLTAGE** 

#### TYPICAL CHARACTERISTICS









**SUPPLY CURRENT** 



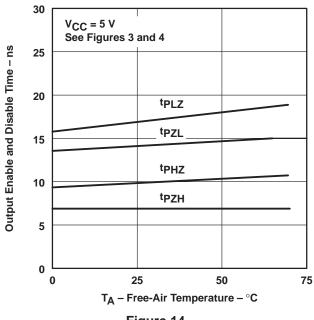
### **TYPICAL CHARACTERISTICS**

# FROM DATA INPUTS FREE-AIR TEMPERATURE 20 Propagtion Delay Time From Data Inputs - ns 18 **tPLH** 16 14 **tPHL** 12 10 8 6 4 V<sub>CC</sub> = 5 V C<sub>L</sub> = 30 pF 2 $R_L = 100 \Omega$ 0 75 0 $T_A$ – Free-Air Temperature – $^{\circ}$ C

Figure 13

PROPAGATION DELAY TIME

**OUTPUT ENABLE AND DISABLE TIME** FREE-AIR TEMPERATURE



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